

**Notice of References Cited**

Application/Control No.

10/563,763

Applicant(s)/Patent Under  
Reexamination  
HAMADA ET AL.

Examiner

EBENEZER SACKY

Art Unit

1624

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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**FOREIGN PATENT DOCUMENTS**

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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Labeeuw et al., Assymetry; Tetrahedron, 15; pages 1899-1908, (2004).
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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